

INTERNATIONAL SEARCH REPORT

International Application No

PCT/FR 02/03422

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 H01L21/762

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 H01L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data, PAJ, INSPEC, IBM-TDB

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	YUN C H ET AL: "Thermal and mechanical separations of silicon layers from hydrogen pattern-implanted wafers" JOURNAL OF ELECTRONIC MATERIALS, AUG. 2001, TMS;IEEE, USA, vol. 30, no. 8, pages 960-964, XP008005517 ISSN: 0361-5235 abstract; figure 1	1-5, 7, 13, 15, 16
Y	---	6, 8-12, 14
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☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

* Special categories of cited documents:

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Date of the actual completion of the international search

15 January 2003

Date of mailing of the international search report

22/01/2003

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	YUN C H ET AL: "Fractional implantation area effects on patterned ion-cut silicon layer transfer" SOI CONFERENCE, 1999. PROCEEDINGS. 1999 IEEE INTERNATIONAL ROHNERT PARK, CA, USA 4-7 OCT. 1999, PISCATAWAY, NJ, USA, IEEE, US, 4 October 1999 (1999-10-04), pages 129-130, XP010370243 ISBN: 0-7803-5456-7 abstract; figure 1 ----	1-5,7, 13,15,16
X	PATENT ABSTRACTS OF JAPAN vol. 1999, no. 05, 31 May 1999 (1999-05-31) -& JP 11 045862 A (DENSO CORP), 16 February 1999 (1999-02-16) abstract; figures ----	1,3-5,7, 13,15,16
X	PATENT ABSTRACTS OF JAPAN vol. 1999, no. 08, 30 June 1999 (1999-06-30) -& JP 11 074208 A (DENSO CORP), 16 March 1999 (1999-03-16) abstract; figures ----	1-5,7, 13,15,16
Y	US 6 054 370 A (DOYLE BRIAN S) 25 April 2000 (2000-04-25) abstract; claims; figures 3-7,10 ----	6,8,9
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